

DESCRIPTION

The ICPLW137, ICPLW2601 and ICPLW2611 devices each consist of an infrared emitting diode, optically coupled to a high speed integrated photo detector logic gate with a strobable output.

These devices belong to Isocom wide body package range optocouplers.

FEATURES

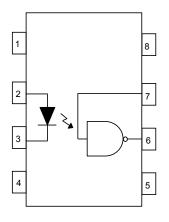
- High Speed 10Mbit/s
- Wide Body Package
- 10kV/µs min. Common Mode Transient Immunity (ICPLW2611)
- High AC Isolation Voltage 5000V_{RMS}
- Guaranteed Performance from -40°C to +85°C
- Strobable Logic Gate Output
- Pb Free and RoHS Compliant
- Safety Approvals Pending

APPLICATIONS

- Line Receivers, Data Communication
- LSTTL to TTL, LSTTL or 5V CMOS
- Data Multiplexing
- Pulse Transformer Replacement
- Switch Mode Power Supplies
- Ground Loop Elimination
- Computer Peripheral Interface

ORDER INFORMATION

- Add SM after PN for Surface Mount,
- Add SMT&R after PN for Surface Mount Tape & Reel



- 1. No Connection
- 2. Anode
- 3. Cathode
- 4. No Connection
- 5. Gnd
- 6. Vout
- 7. V_E
- 8. V_{CC}

A $0.1\mu F$ bypass capacitor must be connected between pins 8 and 5.

ABSOLUTE MAXIMUM RATINGS $(T_A = 25^{\circ}C)$

Input Diode

Forward Current	50mA
Reverse Voltage	5V
Power dissipation	100mW

Output

Output Current	50mA
Output Voltage	7.0V
Supply Voltage	7.0V
Enable Input Voltage	5.5V
(maximum 500mV above V _{CC})	
Power Dissipation	85mW

Total Package

)
C

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Truth Table (Positive Logic)

Input	Enable	Output
Н	Н	L
L	Н	Н
Н	L	Н
L	L	Н
Н	NC	L
L	NC	Н

ELECTRICAL CHARACTERISTICS ($T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$ unless otherwise specified)

INPUT

Parameter	Symbol	Test Condition Min		Тур	Max	Unit
Forward Voltage	V_{F}	$I_F = 10 \text{mA}$		1.4	1.8	V
Reverse Voltage	V_R	$I_R = 100 \mu A, T_A = 25^{\circ}C$ 5.0				V
Temperature Coefficient of Forward Voltage	$\Delta V_F/\Delta T_A$	$I_F = 10 \text{mA}$		-1.9		mV/°C
Input Capacitance	C_{IN}	$V_F = 0V$, $f = 1MHz$	$V_F = 0V, f = 1MHz$ 70			pF

OUTPUT

Parameter	Symbol	Test Condition	Test Condition Min Typ		Max	Unit
High Level Supply Current	I_{CCH}	$I_F = 0$ mA, $V_E = 0.5$ V, $V_{CC} = 5.5$ V 6.5		6.5	10	mA
Low Level Supply Current	I_{CCL}	$I_F = 10 \text{mA}, V_E = 0.5 \text{V}, V_{CC} = 5.5 \text{V}$		13	mA	
High Level Enable Current	$ m I_{EH}$	$V_E = 2.0V, V_{CC} = 5.5V$		-0.6	-1.6	mA
Low Level Enable Current	$ m I_{EL}$	$V_E = 0.5V, V_{CC} = 5.5V$		-0.8	-1.6	mA
High Level Enable Voltage	$ m V_{EH}$	$I_F = 10 \text{mA}, V_{CC} = 5.5 \text{V}$	2.0			V
Low Level Enable Voltage	$ m V_{EL}$	$I_F = 10 \text{mA}, V_{CC} = 5.5 \text{V}$			0.8	V



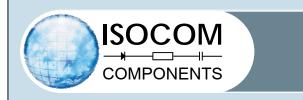
ELECTRICAL CHARACTERISTICS ($T_A = -40^{\circ}$ C to +85°C unless otherwise specified)

COUPLED

Parameter	Symbol	Test Condition Min		Тур	Max	Unit
High Level Output Current	I_{OH}	$V_{CC} = 5.5V, V_E = 2.0V, V_O = 5.5V, I_F = 250\mu A$		2.1	100	μΑ
Low Level Output Voltage	V_{OL}	$V_{CC} = 5.5V, V_E = 2.0V,$ $I_F = 5mA, I_{OL} = 13mA$		0.35	0.6	V
Input Threshold Current	I_{FT}	$V_{CC} = 5.5V, V_E = 2.0V,$ $V_O = 0.6V, I_{OL} = 13mA$		3.0	5	mA

Switching Characteristics ($T_A = -40$ °C to +85°C, $V_{CC} = 5V$, $I_F = 7.5$ mA unless otherwise specified)

Parameter	Symbol	Test Condition	Test Condition Min Typ				
Propagation Delay Time to Output High Level	$t_{\rm PLH}$	$C_L = 15 pF, R_L = 350\Omega,$ $T_A = 25^{\circ}C$			100	ns	
Propagation Delay Time to Output Low level	$t_{ m PHL}$	$C_L = 15 pF, R_L = 350 \Omega,$ $T_A = 25 °C$	0Ω, 40		100	ns	
Pulse Width Distortion	t _{PHL} -t _{PLH}	$C_{L} = 15 \text{pF}, R_{L} = 350 \Omega$		5	40	ns	
Output Rise Time	t _r	$C_{L} = 15 \text{pF}, R_{L} = 350 \Omega$		40		ns	
Output Fall Time	t_{f}	$C_{L} = 15 \text{pF}, R_{L} = 350 \Omega$		10		ns	
Enable Propagation Delay Time to Output High Level	$t_{\rm ELH}$	$I_F = 7.5 \text{mA}, V_{EH} = 3.5 \text{V},$ $C_L = 15 \text{pF}, R_L = 350 \Omega$		15		ns	
Enable Propagation Delay Time to Output Low Level	$t_{ m EHL}$	$I_F = 7.5 \text{mA}, V_{EH} = 3.5 \text{V},$ $C_L = 15 \text{pF}, R_L = 350 \Omega$		15		ns	



ELECTRICAL CHARACTERISTICS ($T_A = -40^{\circ}$ C to +85°C unless otherwise specified)

Switching Characteristics (T_A = -40°C to +85°C, V_{CC} = 5V, I_F = 7.5mA unless otherwise specified)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Common Mode Transient Immunity at Logic High	CM _H	ICPLW137 (Fig 14) $I_{F} = 0mA, V_{OH} (Min) = 2V,$ $R_{L} = 350\Omega, V_{CM} = 10Vp-p,$ $T_{A} = 25^{\circ}C$		5000		V/µs
		ICPLW2601 (Fig 14) $I_{F} = 0mA, V_{OH} (Min) = 2V,$ $R_{L} = 350\Omega, V_{CM} = 50Vp-p,$ $T_{A} = 25^{\circ}C$	5000			
		ICPLW2611 (Fig 14) $I_{F} = 0mA, V_{OH} (Min) = 2V,$ $R_{L} = 350Ω, V_{CM} = 400Vp-p,$ $T_{A} = 25°C$	10000			
		ICPLW2611 (Fig 15) $I_{F} = 0mA, V_{OH} (Min) = 2V,$ $R_{L} = 350Ω, V_{CM} = 400Vp-p,$ $T_{A} = 25°C$	20000			
Common Mode Transient Immunity at Logic Low		ICPLW137 (Fig 14) $I_{F} = 7.5\text{mA}, V_{OL} \text{ (Max)} = 0.8\text{V}, \\ R_{L} = 350\Omega, V_{CM} = 10\text{Vp-p}, \\ T_{A} = 25^{\circ}\text{C}$		5000		V/µs
		ICPLW2601 (Fig 14) $I_F = 7.5\text{mA}, V_{OL} \text{ (Max)} = 0.8\text{V}, \\ R_L = 350\Omega, V_{CM} = 50\text{Vp-p}, \\ T_A = 25^{\circ}\text{C}$	5000			
		ICPLW2611 (Fig 14) $I_F = 7.5\text{mA}, V_{OL} \text{ (Max)} = 0.8\text{V}, \\ R_L = 350\Omega, V_{CM} = 400\text{Vp-p}, \\ T_A = 25^{\circ}\text{C}$	10000			
		ICPLW2611 (Fig 15) $I_F = 7.5\text{mA}, V_{OL} \text{ (Max)} = 0.8\text{V}, \\ R_L = 350\Omega, V_{CM} = 400\text{Vp-p}, \\ T_A = 25^{\circ}\text{C}$	20000			



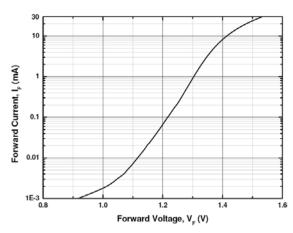


Fig 1 Forward Current vs Forward Voltage

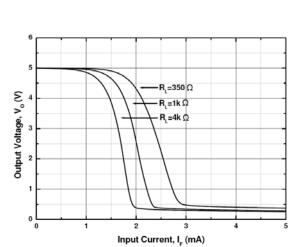


Fig 3 Input Current vs Output Voltage

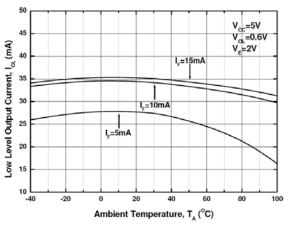


Fig 5 Low Level Output Current vs TA

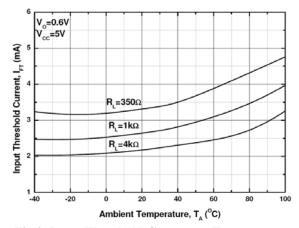


Fig 2 Input Threshold Current vs T_A

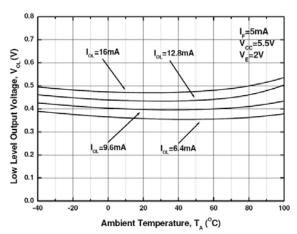


Fig 4 Low Level Output Voltage vs T_A

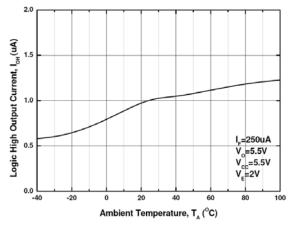


Fig 6 High Level Output Current vs TA



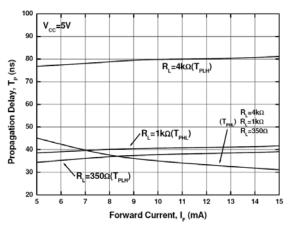


Fig 7 Propagation Delay Time vs Forward Current

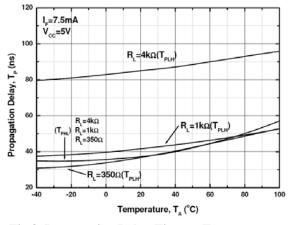


Fig 8 Propagation Delay Time vs T_A

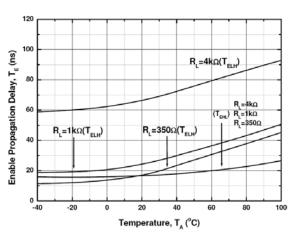


Fig 9 Enable Propagation Delay Time vs T_A

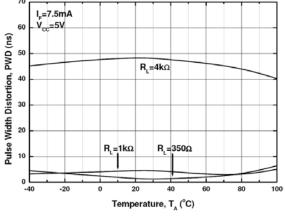


Fig 10 Pulse Width Distortion vs T_A

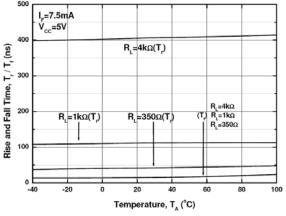


Fig 11 Rise Time / Fall Time vs T_A



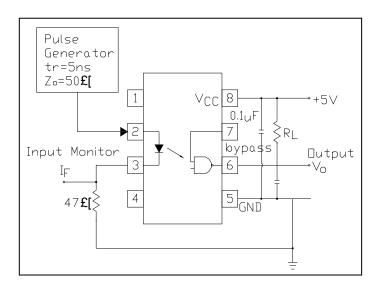
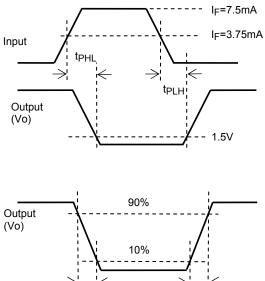
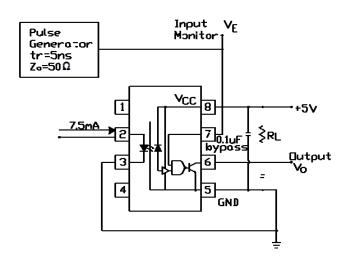


Fig 12 t_{PHL} , t_{PLH} , t_r and t_f Test Circuit





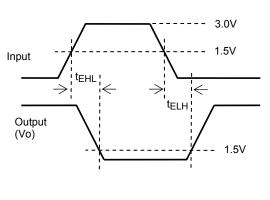
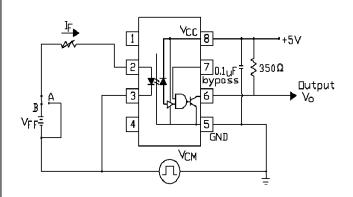


Fig 13 t_{EHL} and t_{ELH} Test Circuit





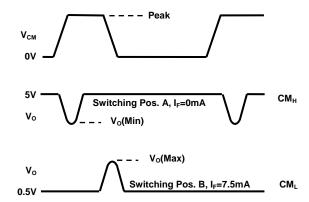


Fig 14 Common Mode Transient Immunity Test Circuit

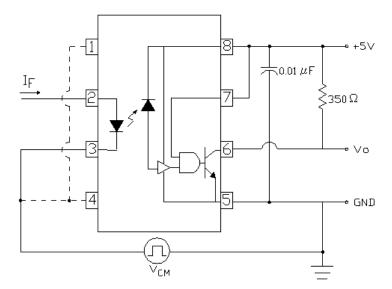


Fig 15 Recommended Drive Circuit for ICPLW2611 for High Common Mode Transient Immunity

 CM_H : Common mode transient immunity in logic high level is the maximum tolerable (positive) dV_{CM}/dt on the leading edge of the common mode pulse signal V_{CM} , to assure that the output will remain in a logic high state (i.e., $V_O > 2.0V$).

 CM_L : Common mode transient immunity in logic low level is the maximum tolerable (negative) dV_{CM}/dt on the trailing edge of the common mode pulse signal, V_{CM} , to assure that the output will remain in a logic low state (i.e., $V_O < 0.8V$).



NOTES:

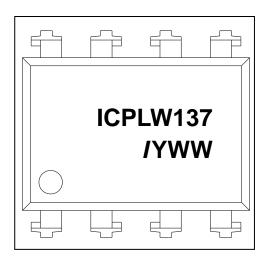
- The V_{CC} supply must be bypassed by a 0.1μF capacitor or larger with good high frequency characteristic and should be connected as close as possible to the package V_{CC} and GND pins.
- Enable Input No pull up resistor required as the device has an internal pull up resistor.
- t_{PLH} is measured from the 3.75mA level on the HIGH to LOW transition of the input current pulse to the 1.5 V level on the LOW to HIGH transition of the output voltage pulse.
- t_{PHL} is measured from the 3.75mA level on the LOW to HIGH transition of the input current pulse to the 1.5 V level on the HIGH to LOW transition of the output voltage pulse.
- t_r Rise time is measured from the 10% to the 90% levels on the LOW to HIGH transition of the output pulse.
- t_f Fall time is measured from the 90% to the 10% levels on the HIGH to LOW transition of the output pulse.
- t_{ELH} is measured from the 1.5V level on the HIGH to LOW transition of the input Enable voltage pulse to the 1.5V level on the LOW to HIGH transition of the output voltage pulse.
- t_{EHL} is measured from the 1.5V level on the LOW to HIGH transition of the input Enable voltage pulse to the 1.5V level on the HIGH to LOW transition of the output voltage pulse.
- CM_H The maximum tolerable rate of rise of the common mode voltage to ensure the output will remain in the HIGH state (i.e., $V_O > 2.0V$).
- CM_L- The maximum tolerable rate of rise of the common mode voltage to ensure the output will remain in the LOW state (i.e., V_O < 0.8V).



ORDER INFORMATION

ICPLW137, ICPLW2601, ICPLW2611							
After PN PN Description Packing quantity							
None	ICPLW137, ICPLW2601, ICPLW2611	Standard DIP	40 pcs per tube				
SM	ICPLW137SMT&R, ICPLW2601SMT&R, ICPLW2611SMT&R	Surface Mount Tape and Reel	500 pcs per reel				

DEVICE MARKING



ICPLW137 denotes Device Part Number (ICPLW137 is used as example)

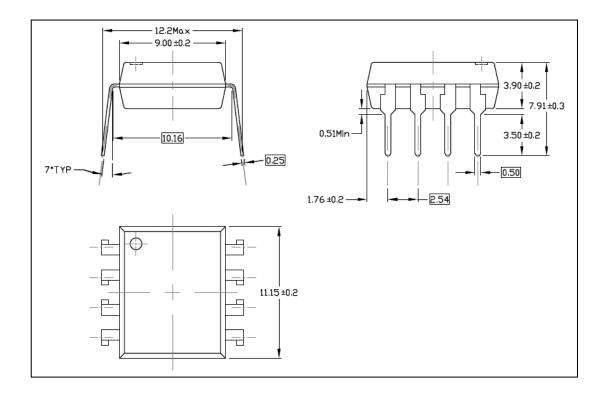
Y denotes 1 digit Year code WW denotes 2 digit Week code

I denotes Isocom

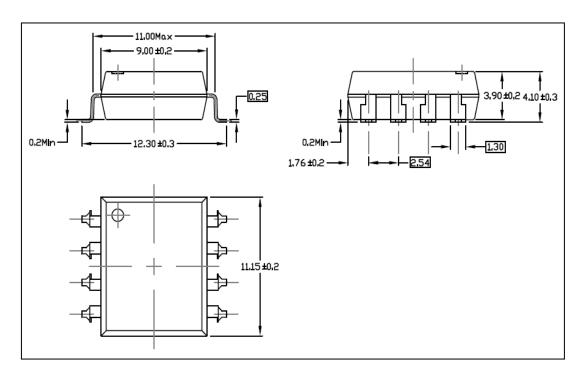


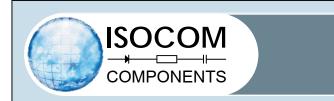
PACKAGE DIMENSIONS (mm)

DIP

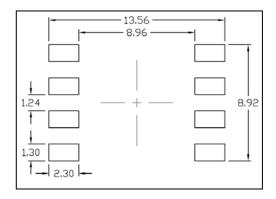


SMD



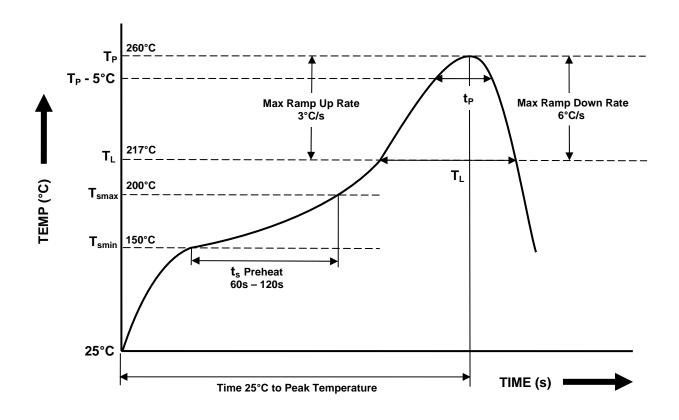


RECOMMENDED PAD LAYOUT FOR SMD (mm)





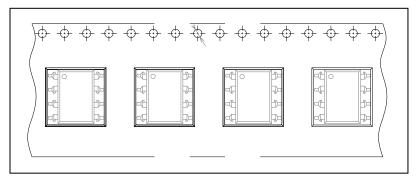
IR REFLOW SOLDERING TEMPERATURE PROFILE (One Time Reflow Soldering is Recommended)



Profile Details	Conditions
$ \begin{array}{l} \textbf{Preheat} \\ \textbf{- Min Temperature } (T_{SMIN}) \\ \textbf{- Max Temperature } (T_{SMAX}) \\ \textbf{- Time } T_{SMIN} \text{ to } T_{SMAX} \left(t_s\right) \end{array} $	150°C 200°C 60s - 120s
	260°C 217°C 30s 60s - 100s 3°C/s max 6°C/s max
Average Ramp Up Rate (T _{smax} to T _P)	3°C/s max
Time 25°C to Peak Temperature	8 minutes max

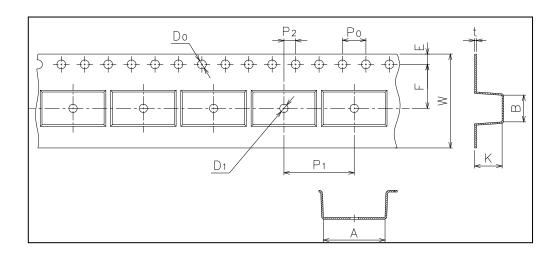


TAPE AND REEL PACKAGING





Direction of feed from reel



Dimension No.	Α	В	Do	D1	E	F
Dimension(mm)	12.7±0.1	11.45±0.1	1.5±0.1	1.5±0.1	1.75±0.1	11.5±0.1
Dimension No.	Ро	P1	P2	t	W	К
Dimension (mm)	4.0±0.1	16.0±0.1	2.0±0.1	0.4±0.05	24.00±0.3	4.6±0.1



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- The products shown in this publication are designed for the general use in electronic applications such as office automation equipment, communications devices, audio/visual equipment, electrical application and instrumentation.
- For equipment/application where high reliability or safety is required, such as space applications, nuclear power control equipment, medical equipment, etc., please contact our sales representatives.
- When requiring a device for any "specific" application, please contact our sales for advice.
- The contents described herein are subject to change without prior notice.
- Do not immerse device body in solder paste.



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